Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
09/782,816	SHARP ET AL.
Examiner	Art Unit

1643

Christopher H. Yaen

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NO (INCLUDING SEARC		·)
	DATE	EXMR
Stic seq searches : SEQ ID No: 3+1+22; SEQ ID No: 51	2/3/2006	СНҮ
palm inventor search	2/3/2006	СНҮ
West- enclosed	2/3/2006	ĊHY